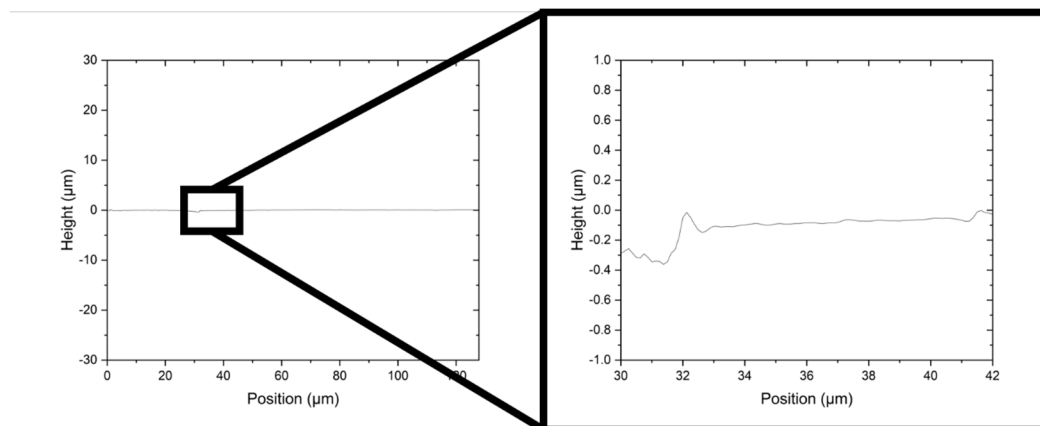
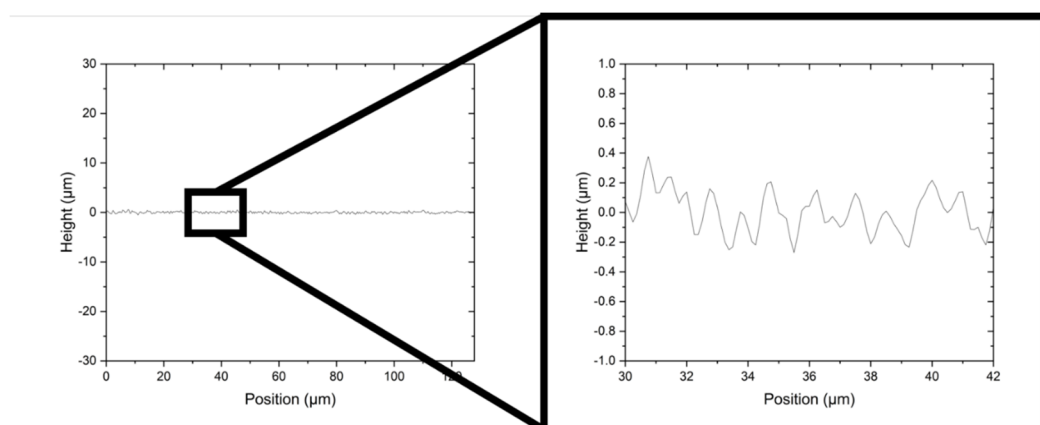


## Supplementary Materials

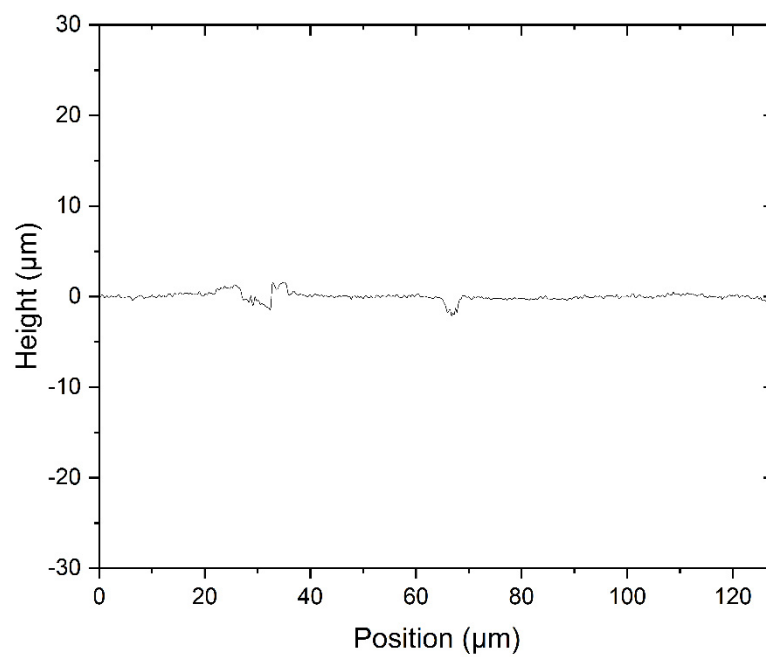
Height elevation profiles for surface structure types (REF, LIPSS, CRATER, MICRO).



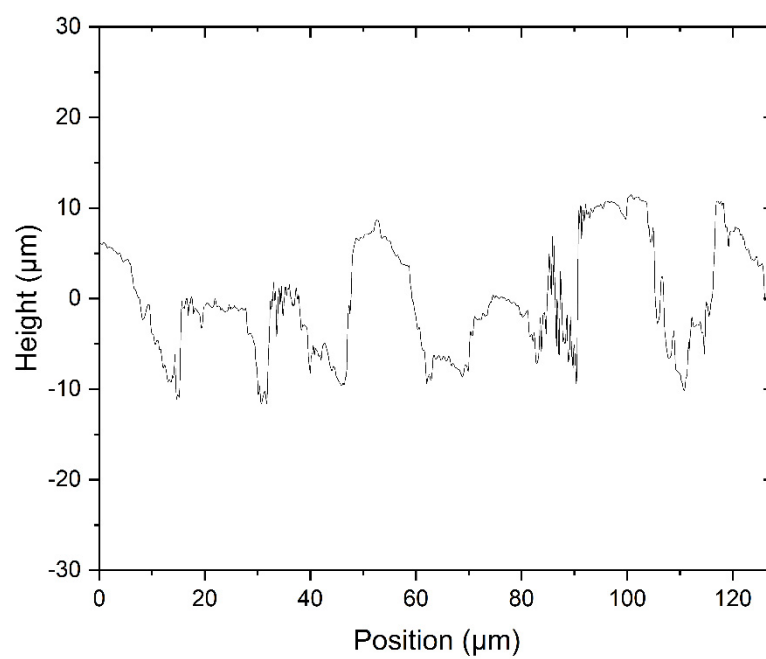
**Figure S1.** Height profile of REF sample with detail.



**Figure S2.** Height profile of LIPSS sample with detail. Measurement was performed perpendicular to the orientation of the LIPSS.



**Figure S3.** Height profile of CRATER sample.



**Figure S4.** Height profile of MICRO sample.